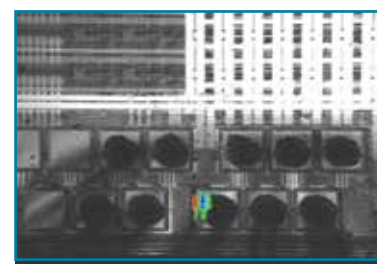
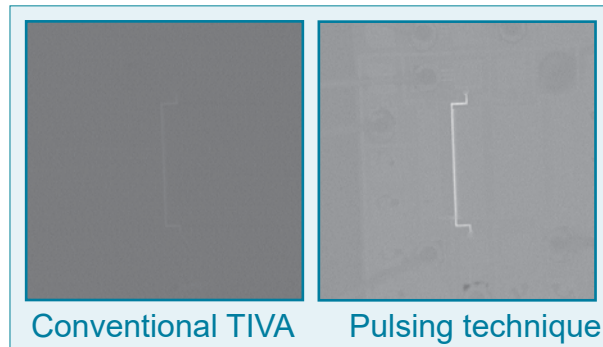


SEMICAPS SOM

SCANNING OPTICAL MICROSCOPY



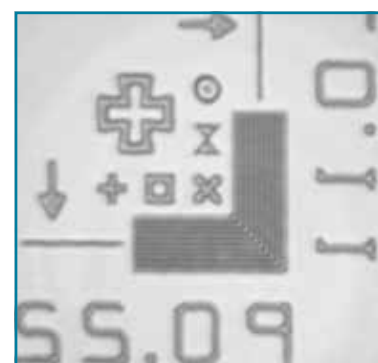
Spot at Bondpad



Spot at Internal Circuitry

Features

- Lasers options - 1340 nm / 1320 nm / 1064 nm with laser scan array size up to 2k x 2k
- Multiple techniques available
 - static : TIVA, OBIRCH
 - dynamic : LADA, SDL
- High power delivery 30 mW at DUT for all objectives including 100x
- Lock-in and Laser Pulsing technique : 10x improvement in sensitivity
- Pixel by pixel flexible scanning mode with user defined multiple - AOI
- Modular platform, field-upgradeable to LTP
- Flexible and customizable
- Centric and Aplanatic Refractive Solid Immersion lens (RSIL) options
- Option to mount PEM cameras (InGaAs, TE-cooled, LN2)



Resolve 110 nm lines through Unthinned Silicon